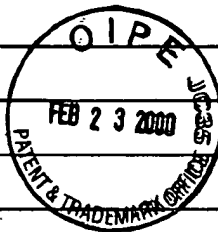


Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
M122-1299SERIAL NO.
09/428,125LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
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2825

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
KR	AA	5,837,591	11/17/98	Shimada et al.			
AB	AB	5,899,740	5/4/99	Kwon			
AC	AC	5,916,634	6/29/99	Fleming et al.			
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						



FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

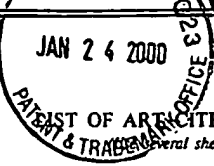
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DATE CONSIDERED

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Form PTO-1449 <div style="text-align: center;">  </div>		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1299		SERIAL NO. 09/428,125	
LIST OF ARTS CITED BY APPLICANT <small>(Indicate all relevant sheets (if necessary))</small>				APPLICANT Micron Technology, Inc.		FILING DATE October 26, 1999	
				GROUP 2825			

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
KR ↓	AA	4,333,808	6/8/82	Bhattacharya et al.			
	AB	5,585,300	12/17/96	Summerfelt			
	AC	5,641,702	6/24/97	Imai et al.			
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	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
KR	AL	JP 405,343,641 (Shimada)	12/1993	Japan	257	310	
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	AN						
	AO						
	AP						

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)		
KR	AR	H. Shnrikt and M. Nakata, IEEE Transaction On Electron Devices vol 38 No 3 March 1991
	AS	
	AT	

EXAMINER <i>Le Rose</i>	DATE CONSIDERED <i>10/9/01</i>
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